

<b>Notice of References Cited</b>	Application/Control No. 10/805,087		Applicant(s)/Patent Under Reexamination MIYANISHI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP2002-148079	05-2002	JP	Inoue, Hitoshi	—/—
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**NON-PATENT DOCUMENTS**

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